

**Search Notes****Application/Control No.**

10/652,496

**Examiner**

Chau Nguyen

**Applicant(s)/Patent under Reexamination**

OHASHI ET AL.

**Art Unit**

2176

**SEARCHED**

Class	Subclass	Date	Examiner
715	517	1/27/2006	CN
715	520	1/27/2006	CN
715	507	1/27/2006	CN
715	505	1/27/2006	CN
715	908	1/27/2006	CN

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Reports	01/26/2006	CN
	1/27/2006	CN
	1/30/2006	CN
NPL Search on IEEE Database	1/30/2006	CN
Updated Search on East Reports	7/13/2006	CN
Updated Search on East Reports	2/23/2007	CN
	2/26/2007	CN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner